Deep PCB Defect Detection Project

Abstract

This document describes the development of a deep learning-based system for detecting defects in Printed Circuit Boards (PCBs) using image data. The system involves data preprocessing steps to prepare the training data, creation of a suitable dataset, and a Convolutional Neural Network (CNN) architecture for automated defect classification (unet architect).

Data Preprocessing

- Data Path Definition: The file paths for the training data directory, normal image directory, and defect image directory are defined.
- Parsing Label and Image Paths: Text files containing lists of image paths and corresponding labels are parsed to create separate lists for normal and defect images with their associated labels.
- Image Loading and Preprocessing: Images are loaded, converted to grayscale format, and resized to a uniform size (128x128 pixels).
- Label Processing: Label text files are parsed to generate a list of bounding boxes representing defect regions within each image.

Dataset Creation

- Combined Dataset: A combined dataset is formed by merging the preprocessed normal and defect images with their corresponding labels and bounding boxes.
- Data Shuffling: The dataset is shuffled to randomize the order of data points,
 mitigating potential biases during training.

 Train-Test Split: The shuffled dataset is divided into training and testing sets using an 80/20 ratio. The training set is further batched for efficient model training.

Model Building

- Convolutional Neural Network (CNN) Architecture: The core of the system is a CNN architecture designed for defect detection.
- He Normal Initialization: He Normal initialization is employed for weight biases in the convolutional layers to address the "dying ReLU" problem and improve training efficiency.
- ReLU Activation: The ReLU (Rectified Linear Unit) activation function is used throughout the convolutional layers to introduce non-linearity into the network.
- Encoder-Decoder Structure: The network follows an encoder-decoder structure:
 - Encoder: This part performs feature extraction through convolutional and pooling operations. The image size progressively reduces while the number of feature channels increases, capturing informative features from the input images.
 - Center Cropping: In the encoder path, center cropping is used to focus on relevant defect areas within the image.
 - Decoder: The decoder upsamples the extracted features and combines them with corresponding cropped features from the encoder path, enabling precise defect localization.
 - Concatenation: Feature maps from different parts of the network are merged using concatenation to improve the model's ability to detect defects.

Output Layer: The final layer of the CNN has 7 filters, corresponding to the 7
 different defect classes the model aims to identify.

Model Training and Evaluation

- Adam Optimizer: The Adam optimizer is used to train the model, which efficiently updates the network weights based on the calculated loss.
- Sparse Categorical Crossentropy Loss: The Sparse Categorical Crossentropy loss function is employed to measure the difference between the predicted defect classes and the ground truth labels during training.
- Validation Dataset: A validation dataset is used to monitor model performance during training and prevent overfitting.

Result:





